# IEC/IEEE 60802 to IECEE Reference Model

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# Mission and Scope of IEC/IEEE 60802
# and the relation to IECEE conformance test

## IA profile is intended to state

- the used standards

  - the mandatory to be supported features out of these standards
  - the optional to be supported features out of these standards
  - the to be excluded features out of these standards

  - the mandatory quantities for the mandatory and optional features

  - the managed objects assigned to the mandatory and optional features and their be supported values and value ranges
  - the MIBs and/or YANG modules representing these managed objects

- the Device Description content to specify the features and quantities a dedicated device is supporting
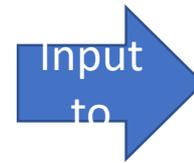
**Input to** → IECEE creates test specification to verify all mandatory and optional features of the IEC/IEEE 60802 with the values from the "Device Description" **Basis for** → **Device Test**

**Input to** ↑
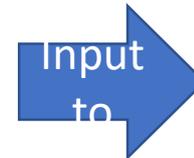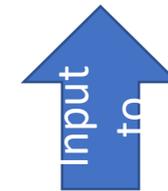
**Input to** → Device supplier provides a "Device Description" to specify the features this device is supporting.

# Questions?